

SCRs

1.6 Amp, Planar

2N2322-2N2329
2N2323A-2N2328A

FEATURES

- Available as JAN, JANTXV & JANTXV Types
- 1.6A D.C. Current
- Peak Currents: to 30A
- Voltage Ratings: to 400V
- 20 μ A Max. Trigger Current ("A" types)
- 0.6V Max. Trigger Voltage ("A" types)

DESCRIPTION

These are premium thyristor switches intended for use in high performance industrial, military and space applications requiring a high degree of reliability assurance. This series is useful in a wide variety of applications including timing and programming circuits, protective and warning circuits, driving relays, driving indicator lamps, encoding and decoding circuits, replacing relays, thyratrons, and magamps, servo motor control, pulse generation, plus many others. The high surge current rating (15A - 1 cycle) makes this series particularly useful for squib firing.

The following JAN, JANTX and JANTXV types are specified under Mil-S-19500/276A and are included in Mil-STD-701 as recommended types for military usage:

ABSOLUTE MAXIMUM RATINGS

| | 2N2323 JAN2N2323 JANTX2N2323 JANTXV2N2323 | 2N2324 JAN2N2324 JANTX2N2324 JANTXV2N2324 | 2N2325 | 2N2326 JAN2N2326 JANTX2N2326 JANTXV2N2326 | 2N2327 | 2N2328 JAN2N2328 JANTX2N2328 JANTXV2N2328 | 2N2329 JAN2N2329 JANTX2N2329 JANTXV2N2329 | |
|--|--|--|--------|--|--------|--|--|-----------------|
| Repetitive Peak Off-State Voltage, V_{DRM} | 25V | 50V | 100V | 150V | 200V | 250V | 300V | 400V |
| Repetitive Peak Reverse Voltage, V_{RRM} | 25V | 50V | 100V | 150V | 200V | 250V | 300V | 400V |
| Non-Repetitive Peak Reverse Voltage, V_{RSM} (< 5ms) | 40V | 75V | 150V | 225V | 300V | 350V | 400V | 500V |
| D.C. On-State Current, I_T | | | | | | | | 300mA |
| | | | | | | | | 80°C Ambient |
| | | | | | | | | 85°C Case |
| One Cycle Surge (Non-Rep.) On-State Current, I_{TSM} | | | | | | | | 1.6A |
| Repetitive Peak On-State Current, I_{TM} | | | | | | | | 15A |
| Gate Power Dissipation, P_{GM} | | | | | | | | 30A |
| Gate Power Dissipation, $P_{GM(AV)}$ | | | | | | | | 0.1W |
| Peak Gate Current, I_{GM} | | | | | | | | 0.01W |
| Peak Gate Voltage, Forward and Reverse | | | | | | | | 100mA |
| Reverse Gate Current, I_{GR} | | | | | | | | 6V |
| Storage Temperature Range | | | | | | | | 3mA |
| Operating Temperature Range | | | | | | | | -65°C to +150°C |
| | | | | | | | | -65°C to +125°C |

MECHANICAL SPECIFICATIONS

2N2322-2N2329 2N2323A-2N2328A

| | in. | mm. |
|---|---------------------|--------------------|
| A | 305-335 | 7.75-8.51 |
| B | 335-370 | 8.51-9.40 |
| C | 240-260 | 6.35-6.60 |
| D | 010-030 | 25-76 |
| E | 5 MIN | 12.70 MIN |
| F | .017 ± .002 .001 | 432 ± .051 .025 |
| G | 200 | 5.08 |
| H | 100 | 2.54 |
| J | 031 ± 003 | .79 ± .08 |
| K | 029-045 | .74-1.14 |
| L | 100 | 2.54 |

TO-5 has 1.5" (38.10mm) lead length

TO-39

JAN types available in TO-5 package upon request.

ELECTRICAL SPECIFICATIONS

| Test | Symbol | Min. | Typical | Max. | Units | Test Conditions |
|---|-----------|-------|---------|------|------------|---|
| Visual and Mechanical | | | | | | MIL-STD-750, Method 2071 |
| 25°C | | | | | | |
| Off-State Current | I_{DRM} | — | 0.1 | 10 | μA | $V_{DRM} = \text{Rating}, R_{GK} = 1K$ (2K for "A" Types) |
| Reverse Current | I_{RRM} | — | 0.1 | 10 | μA | $V_{RRM} = \text{Rating}, R_{GK} = 1K$ (2K for "A" Types) |
| Gate Trigger Current | I_{GT} | — | 2 | 20 | μA | $V_D = 6V, R_L = 100\Omega$ |
| "A" Types | | — | 2 | 20 | μA | $V_D = 6V, R_L = 100\Omega$ |
| non-"A" Types | | — | 50 | 200 | μA | $V_D = 6V, R_L = 100\Omega$ |
| Gate Trigger Voltage | V_{GT} | 0.35 | 0.52 | 0.60 | V | $V_D = 6V, R_{GK} = 2K, R_L = 100\Omega$ |
| "A" Types | | 0.35 | 0.55 | 0.80 | V | $V_D = 6V, R_{GK} = 1K, R_L = 100\Omega$ |
| non-"A" Types | | — | 2.0 | 2.2 | V | $I_{TM} = 4A$ (pulse test) |
| On-State Voltage | V_{TM} | — | 2.0 | 2.2 | V | $V_D = 6V, R_{GK} = 1K$ (2K for "A" Types) |
| Holding Current | I_H | — | 0.3 | 2.0 | mA | $V_{GK} = 6V$ |
| Reverse Gate Current | I_{GR} | — | 1 | 200* | μA | $I_G = 10mA, I_T = 1A, V_D = 30V$ |
| Delay Time | t_d | — | 0.6 | — | μS | $I_G = 10mA, I_T = 1A, V_D = 30V$ |
| Rise Time | t_r | — | 0.4 | — | μS | $I_T = 1A, I_R = 1A, R_{GK} = 1K$ |
| Circuit Commutated Turn-Off Time | t_q | — | 20 | — | μS | |
| 125°C | | | | | | |
| Off-State Current | I_{DRM} | — | 1 | 100 | μA | $V_{DRM} = \text{Rating}, R_{GK} = 1K$ (2K for "A" Types) |
| Reverse Current | I_{RRM} | — | 1 | 100 | μA | $V_{RRM} = \text{Rating}, R_{GK} = 1K$ (2K for "A" Types) |
| Gate Trigger Voltage | V_{GT} | 0.1 | 0.3 | — | V | $V_D = \text{Rated } V_D, R_{GK} = 1K$ (2K for "A" Types) |
| Holding Current | I_H | 0.1† | — | — | mA | $V_D = 6V, R_{GK} = 2K$ |
| "A" Types | | 0.15† | — | — | mA | $V_D = 6V, R_{GK} = 1K$ |
| non-"A" Types | | | | | | |
| Off-State Voltage — Critical Rate of Rise | dv/dt | 0.7* | — | — | V/ μS | $V_D = \text{Rating}, R_{GK} = 2K$ |
| "A" Types | | 1.8* | — | — | V/ μS | $V_D = \text{Rating}, R_{GK} = 1K$ |
| non-"A" Types | | | | | | |
| —65°C | | | | | | |
| Off-State Current | I_{DRM} | — | .05 | 5.0* | μA | $V_{DRM} = \text{Rating}, R_{GK} = 1K$ (2K for "A" Types) |
| Reverse Current | I_{RRM} | — | .05 | 5.0* | μA | $V_{RRM} = \text{Rating}, R_{GK} = 1K$ (2K for "A" Types) |
| Gate Trigger Current | I_{GT} | — | 50 | 75 | μA | $V_D = 6V, R_L = 100\Omega$ |
| "A" Types | | — | 100 | 350 | μA | $V_D = 6V, R_L = 100\Omega$ |
| non-"A" Types | | | | | | |
| Gate Trigger Voltage | V_{GT} | — | 0.7 | 0.8* | V | $V_D = 6V, R_{GK} = 2K, R_L = 100\Omega$ |
| "A" Types | | — | 0.75 | 0.9† | V | $V_D = 6V, R_{GK} = 2K, R_L = 100\Omega$ |
| non-"A" Types | | — | 0.75 | 1.0 | V | $V_D = 6V, R_{GK} = 1K, R_L = 100\Omega$ |
| Holding Current | I_H | — | — | 3.0† | mA | $V_D = 6V, R_{GK} = 1K$ (2K for "A" Types) |

* JAN and JANTX Types only.

† Industrial Types only.

X

JAN and JANTX Acceptance Tests

100% Screening TX-Types

High Temperature Storage
 Temperature Cycling
 Constant Acceleration
 Fine & Gross Hermetic Seal
 Electrical Test
 Burn-in
 Electrical Test

Group B Tests

Subgroup 1 — Reverse Gate Current
 Surge Current
 Non-Repetitive Reverse Voltage

Subgroup 2 — Low Temp. Reverse Blocking Current
 Low Temp. Forward Blocking Current
 Low Temp. Gate Trigger Voltage
 Low Temp. Gate Trigger Current

Subgroup 3 — Temperature Cycling
 Thermal Shock
 Moisture Resistance
 Solderability

Subgroup 4 — Blocking Life Test

Group C Tests

Subgroup 1 — Physical Dimensions

Subgroup 2 — Shock
 Constant Acceleration
 Vibration, Variable Frequency

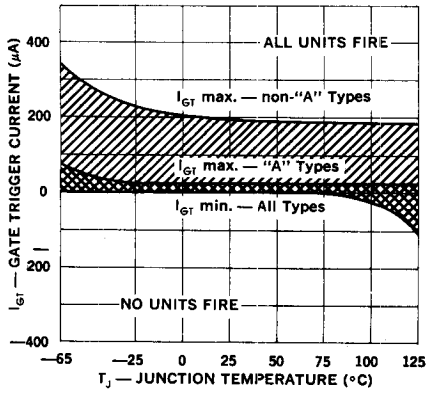
Subgroup 3 — Barometric Pressure, Reduced

Subgroup 4 — Salt Atmosphere

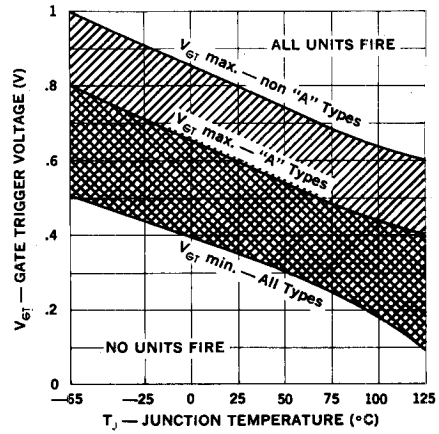
Subgroup 5 — Terminal Strength

Subgroup 6 — Intermittent Operating Life Test

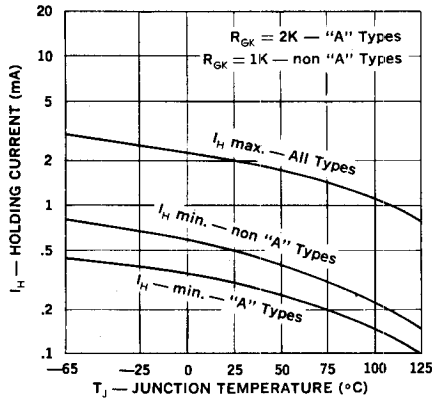
Gate Trigger Current



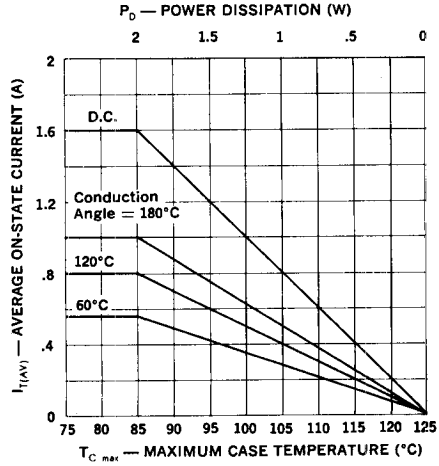
Gate Trigger Voltage



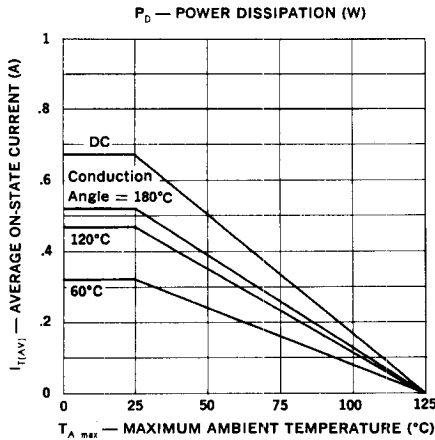
Holding Current



Average Current vs. Case Temperature



Average Current vs. Ambient Temperature



Surge Current

